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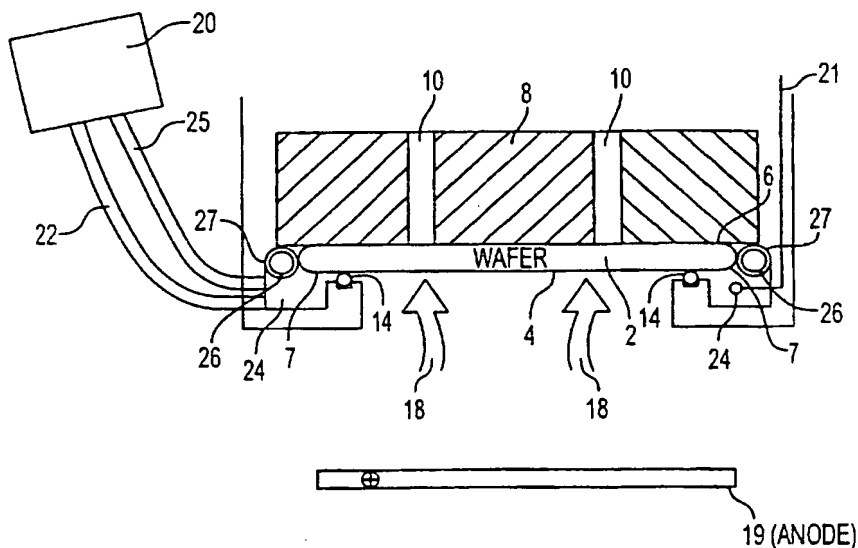
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(54) Title: METHOD AND APPARATUS FOR FORMING AN ELECTRICAL CONTACT WITH A SEMICONDUCTOR SUBSTRATE



(57) Abstract: The present invention is directed to a method and apparatus for plating a surface of a semiconductor workpiece (wafer, flat panel, magnetic films, etc.) using a liquid conductor that makes contact with the outer surface of the workpiece. The liquid conductor is stored in a reservoir and pump through an inlet channel to the liquid chamber. The liquid conductor is injected into a liquid chamber such that the liquid conductor makes contact with the outer surface of the workpiece. An inflatable tube is also provided to prevent the liquid conductor from reaching the back face of the workpiece. A plating solution can be applied to the front face of the workpiece where a retaining ring/seal further prevents the plating solution and the liquid conductor from making contact with each other. Further, this invention can be used to dissolve/etch a metal layer from the periphery of the workpiece.

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METHOD AND APPARATUS FOR FORMING AN ELECTRICAL CONTACT WITH A SEMICONDUCTOR SUBSTRATE

Field of the Invention

5 This invention relates generally to a method and apparatus for electroplating a metal on a semiconductor substrate. More particularly, the invention is directed to a method and apparatus for forming electrical contacts on the semiconductor substrate using a liquid conductor during the plating process. Alternatively, electrical contacts may be formed using an inflatable tube that has either been coated with a conductive material or contains a conductive object. Furthermore, the invention
10 provides a method and apparatus for dissolving/etching a metal layer from the substrate edge.

Background of the Invention

Plating is an important and necessary step in the high performance chip fabrication process. When plating, it is necessary to form a good ohmic contact with a seed layer on/or near a circumfe-
15 rential edge of a substrate. Different conventional techniques exist to accomplish this task. According to one technique, for example, a great number of contact fingers, upwards of 130, are used to form contacts with the seed layer on the circumferential edge of a wafer. The contact fingers, which are typically metallic, are coupled to the circumferential edge of the wafer in accordance with any known method.

20 Fig. 1A illustrates a top view of a conventional configuration showing contact fingers 12 coupled to the wafer 2 during the plating process. As illustrated, a large number of contact fingers 12 extending from a housing 11 are evenly distributed around the circumferential edge 7 of the wafer 2. The housing 11 has a ring shape corresponding to the shape of the circumferential edge 7 of the wafer 2. An electric potential (cathode) is then applied to the wires 13 or housing 11 that are further
25 coupled to the contact fingers 12 within the housing 11. This, in turn, provides the electric potential to the circumferential edge 7 of the wafer 2, thereby allowing the wafer surface to be plated. Instead of using the contact fingers 12 as described above, the electric potential can be applied to the wafer using a ring conductor.

Fig. 1B illustrates a cross sectional view of a conventional plating apparatus as described with
30 reference to Fig. 1A. An entire back face 6 of the wafer 2 rests against a conventional chuck 8, and a vacuum 10 is used to ensure that the wafer 2 is stationary with respect to the chuck 8 while loading and/or plating the wafer 2. Regions adjacent to the circumferential edge 7 of the front face 4 of the wafer 2 are coupled to the contact fingers 12 as described above. A plating solution, typically a metal solution, is flowed in the direction of arrow 18 to the front face 4 of the wafer 2. When an electric
35 potential is applied between an anode electrode 19, and the circumferential edge 7 of the wafer 2, the front face 4 of the wafer can be plated with the metal species contained in the plating solution.

Contact fingers are critical components of the wafer plating process as they provide the necessary electrical potential to the wafer. However, conventional plating systems such as described above have many drawbacks and disadvantages. For example, during the plating process, metal from the plating solution may be electroplated on the contact fingers, thereby generating contaminating particles. In addition, the electroplated metal on the contact fingers increases contact resistance resulting in a high voltage drop and failure. Moreover, over time, the contact fingers are susceptible to corrosion and/or fatigue. Failure of such contact fingers then leads to non-uniform wafer plating, which may cause irreparable damage to the semiconductor wafer, thereby resulting in lost products and revenues for the manufacturer.

Thus, there remains a need for a semiconductor substrate plating method and apparatus that provides plating in a dependable and reliable manner. Accordingly, a more consistent method and apparatus for providing an electrical contact to a semiconductor substrate during plating is needed.

Summary of the Invention

It is an object of the present invention to provide a method and apparatus that provides electric potential to the wafer using a liquid conductor.

It is another object of the invention to provide a method and apparatus that plates the front face of the wafer while preventing the plating solution from reaching the back face and edge of the wafer.

It is a further object of the invention to provide a method and apparatus that plates the front face of the wafer while preventing the liquid conductor from reaching the back face of the wafer.

It is yet another object of the present invention to provide a method and apparatus that recycles the liquid conductor.

It is a further object of the invention to provide a method and apparatus that dissolves/etches a metal layer from the periphery of the wafer.

It is another object of the invention to provide a method and apparatus that provides electric contacts to the wafer using an inflatable tube that has been coated with a conductive material.

It is a further object of the invention to provide a method and apparatus that plates a semiconductor workpiece such as wafers, flat panels, and magnetic films in a reliable and dependable manner.

It is yet another object of the invention to provide a more efficient method for establishing electrical contacts with the wafer.

These and other objects are obtained by providing a method and apparatus that plates a semiconductor wafer using a liquid conductor as the electrical contacts. This invention includes a liquid chamber for holding the liquid conductor during the plating process. The liquid conductor is stored in a reservoir and pump through an inlet channel to the liquid chamber. A tube is inflated to seal the

back face of the wafer, and the liquid conductor is injected into the liquid chamber such that the liquid conductor makes contact with the circumferential edge of the wafer. An electric potential is applied to the liquid conductor. Then, a plating solution is applied to the front face of the wafer. After plating the wafer, the used liquid conductor is removed from the liquid chamber through an outlet channel. Subsequent wafers are processed, each time using a fresh liquid conductor.

Alternatively, the inflatable tube may be coated with a conductive material to form electric contacts with the circumferential edge of the wafer. In this embodiment, the liquid conductor is not needed.

A further implementation of the method and apparatus of the invention is to provide an acid or etching solution to the chamber such that the metal layer on the periphery of the wafer can be dissolved/etched.

Brief Description of the Drawings

These and other objects and advantages of the invention will become apparent and more readily appreciated from the following detailed description of the presently preferred exemplary embodiment of the invention taken in conjunction with the accompanying drawings, of which:

Fig. 1A illustrates a top view of a conventional configuration of the contact fingers coupled to a wafer during the wafer plating process;

Fig. 1B illustrates a cross sectional view of a conventional plating apparatus;

Fig. 2 illustrates a cross sectional view of a plating apparatus using a liquid conductor in accordance with the preferred embodiment of the invention;

Fig. 3 illustrates an enlarged cross sectional view of a liquid chamber in accordance with the preferred embodiment of the invention;

Figs. 4A - 4B illustrate top views of a plating apparatus using the liquid conductor in accordance with the preferred embodiment of the invention;

Fig. 5 illustrates a cross sectional view of a plating apparatus using a coated inflatable tube in accordance with another preferred embodiment of the invention;

Figs. 6A - 6B illustrate top views of a plating apparatus using the coated inflatable tube in accordance with the preferred embodiments of the invention; and

Figs. 7A - 7B illustrate cross sectional views of an inflatable tube having a conductive object in accordance with the preferred embodiment of the invention.

Detailed Description of the Preferred Embodiments

The preferred embodiments of the invention will now be described with reference to Figs. 2-7, wherein like components are designated by like reference numerals throughout the various figures.

In the first embodiment, the present invention is directed to a method and apparatus that uses a liquid

conductor as electrical contacts on the wafer during the wafer plating process. The liquid conductor is preferably a solution containing indium, tin, gallium, mercury, acid, salt solution, or the like. Other alloys containing indium, tin, gallium, mercury, acid, salt solution, or the like may be used in accordance with the present invention. Since the liquid conductor should be in liquid phase at
5 operating temperature and during the plating process, the melting point thereof will typically be in the range of 10 °C to 40 °C.

In addition to the various types of solutions mentioned above, metal powders mixed with another solution may be used in accordance with the present invention as electric contacts on the wafer during the wafer plating process. For example, metal powders can be mixed with a carrier
10 fluid, for example water, and delivered to the liquid chamber. Thus, what is important to note from this example is that metal powders mixed with a fluid and delivered to the liquid chamber may be used in lieu of the various types of solutions mentioned earlier.

Furthermore, although a semiconductor wafer will be used to describe the preferred embodiment of the invention, other semiconductor workpiece such as a flat panel or magnetic film
15 may be used in accordance with the invention.

Fig. 2 illustrates a cross sectional view of a plating apparatus in accordance with the preferred embodiment of the invention. Similar to Fig. 1, the wafer 2 has a front face 4 and a back face 6 resting against the chuck 8. A vacuum 10 is used to ensure that the wafer 2 is stationary with respect to the chuck 8 while the wafer 2 is being loaded and/or plated.

In the preferred embodiment of the invention, a liquid conductor, rather than the contact fingers 12 as described with reference to Fig. 1, is used to form an ohmic contact with the circumferential edge 7 or regions adjacent to the front face 4 of the wafer 2. The liquid conductor is stored in a reservoir 20, which may be a single reservoir or multiple reservoirs. The liquid conductor is pumped from the reservoir 20 using a conventional pump (not shown) through an inlet channel 22
20 and injected into a liquid chamber 24. More than one pump may be used to pump the liquid conductor into the liquid chamber 24 when multiple reservoirs are used.

Fig. 3 illustrates an enlarged cross sectional view of the liquid chamber 24 in accordance with the preferred embodiment of the invention. To form the liquid chamber 24 and prevent the liquid conductor from flowing to the back face 6 of the wafer, a tube 26 is inflated with gas before the liquid
30 conductor is pumped/injected into the chamber 24. Thus, the inflated tube 26 seals the back face 6 of wafer 2 from the liquid conductor. The tube 26 is preferably made of an elastomer or reinforced elastomer material or other material that is flexible enough to form a liquid tight seal when inflated against the wafer 2 and the retaining wall 27 of the chamber 24. The tube 26 should also be strong enough to support the pressure of the injected gas.

In its deflated state, the tube 26 is attached to and rests in a groove along the retaining wall 27. When gas is injected from a gas source (not shown) through a gas line 31 that is connected to the inside of the tube 26, the tube 26 inflates until it makes a liquid tight seal against the edge of the wafer 2 and the retaining wall 27. At this stage, no additional gas is injected into the tube 26. The gas may be air, nitrogen, inert gas, or any other gas that is capable of inflating the tube 26. A valve can be provided to adjust the pressure and the gas flow rate depending on the size of the wafer and/or size of the chamber 24. Additionally, the gas line 31 can be used to remove the gas when deflating the tube 26. The tube 26 preferably has a bicycle inner-tube shape or bladder, corresponding to the shape of the circumferential edge 7 of the wafer 2.

Referring back to Figs. 2 and 3, a nonconductive retainer ring/seal 14 is used to prevent the plating solution from reaching the back face 6 and the circumferential edge 7 of the wafer 2. The retaining ring/seal 14, shaped in the ring, is positioned on the wafer 2 between the liquid chamber 24 and the center of the wafer 2. The ring/seal 14 is preferably positioned less than 10 mm from the wafer edge. The retaining ring/seal 14 preferably pushes against a seed layer 5 on the front face 4 of the wafer 2 holding the wafer in proper position. A liquid tight sealed is obtained with the retainer ring/seal 14 so that the liquid conductor and the plating solution are kept isolated from each other. Thus, the entire back face 6 of the wafer 2 that rests against the chuck 8 and the front surface areas (typically the outer 1-10 mm surface) of the wafer 2, which are under the retaining ring/seal 14, are protected from the plating solution.

The liquid conductor is pumped and injected into the fluid chamber 24 via the inlet channel 22. A contact ring 28 may include a tunnel 30 such that the liquid conductor can be pumped/injected through the contact ring 28. When the liquid chamber 24 is filled, the liquid conductor 22 makes contact with the circumferential edge 7 of the wafer 2. When such contact is established, an electrical potential (cathode) can be applied to the liquid conductor 22 via wire/probe 21. Thus, the circumferential edge 7 of the wafer 2 also receives the same electric potential. A plating solution is then flowed in the direction of arrows 18 from an anode plate 19 to the front face 4 of the wafer 2. The liquid conductor 22 forms the ohmic contact with the wafer 2 such that plating is substantially uniform across the front face 4 of the wafer 2.

After plating the wafer 2, the liquid conductor in the liquid chamber 24 is removed via an outlet channel 25 to the reservoir 20 or a recycling reservoir (not shown). After removing the used liquid conductor, a fresh liquid conductor is pumped/injected into the chamber 24 for processing the next wafer. The present invention contemplates recycling the used liquid conductor via the recycling reservoir. Using the recycled liquid conductor reduces the costs associated with the current plating process, while providing a more efficient method of providing electric contacts.

Figs. 4A - 4B illustrate top views of the plating apparatus of Figs. 2 - 3 in accordance with the preferred embodiments of the present invention. First, from the top view, the liquid chamber 24 preferably has a ring shape with an inner radius 32 and an outer radius 36 from the center of the wafer 2. The wafer 2 has a radius 34 that is between the inner radius 32 and the outer radius 36 of the liquid chamber 24. The liquid conductor is pumped/injected into the liquid chamber 24 through an inlet channel 22 from the reservoir 20. Because of the ring shape, the liquid conductor in the liquid chamber 24 makes contact with the entire circumferential edge 7 of the wafer 2, which may include regions that are 1-10 mm from the wafer edge. Fig. 4A also illustrates an outlet channel 25 for removing the liquid conductor from the liquid chamber 24.

In another embodiment, multiple liquid chambers may be used in accordance with the present invention. Fig. 4B illustrates four compartmentalized liquid chambers 40. The compartmentalized liquid chambers 40 have the same inner radius 32 and the same outer radius 36 as in the liquid chamber 24 of Fig. 4A. The wafer radius 34 is also the same as that illustrated in Fig. 4A. In this configuration, four reservoirs 20 containing the liquid conductor may be used to provide the liquid conductor to each corresponding liquid chambers 40. The liquid conductor from each reservoir 20 is flowed through the corresponding inlet channels 22 into its respective liquid chambers 40. Because the liquid chambers 40 are compartmentalized, the liquid conductor contained therein makes contact with the circumferential edge 7 of the wafer only at those sections. The electric potential is applied to the liquid conductors in the four liquid chambers 40, thereby resulting in the electric potential being applied to the corresponding four sections of the wafer 2. Also, each liquid chamber 40 includes an outlet channel for removing the used liquid conductor.

Although four compartmentalized liquid chambers 40 are illustrated in Fig. 4B, more or less than four chambers may be used in accordance with the present invention.

Additionally, one skilled in the art will recognize that the present invention can be implemented using liquid chambers having various sizes and shapes than those described in Fig. 4A and 4B.

The invention can further be used to dissolve/etch metal films from the edge and regions around the edge of a semiconductor substrate. It is very desirable to remove spurious metal or seed layer from the edge or backside of the wafer, since the metal films are not affected by chemical-mechanical process. The presence of these undesirable metals or poorly adhering film may lead to equipment contamination and cross-contamination when the flakes are sheered off the substrate. For example, the invention may be used to dissolve a Cu seed layer or spurious Cu films at the wafer edge 7 or at any portion of the wafer that is enclosed by chamber 24, or any portion of the wafer between the seal 14 and another seal (not shown) on the wafer backside 6.

15 In the embodiment of Fig. 5, a tube 100 is coated with a conductive material such that when the tube 100 is inflated, the tube 100 is capable of making an electric contact with the circumferential edge 7 of the wafer 2. The tube 100 is preferably coupled to an electric contact 102 (wire) for applying an electric potential (cathode) to the tube 100. The outer tube surface is preferably coated with a conductive material such as metal or polymer. The tube 100 further provides uniform contact
20 and pressure along the periphery of the wafer, which may not necessarily be perfectly flat, because the tube 100 can conform according to the shape of the circumferential edge 7 of the wafer 2. Thus, in this embodiment, a liquid conductor is no longer needed because the tube 100 can be used as the cathode contact with the wafer 2.

In another embodiment, multiple tubes 200 may be used in accordance with the present invention. In Fig. 6B, four tubes 200 are used, and each tube 200 has the same inner radius 104 and the same outer radius 106 as described above. The wafer radius 108 again is between the inner radius 104 and the outer radius 106. Each wire 102 is coupled to an outer surface of the corresponding tube

200. Because the tubes 200 are spaced apart from each other, they form electric contacts with the circumferential edge 7 of the wafer 2 only at four sections. An electric potential can be applied to the four tubes 200, thereby providing the same electric potential to the wafer 2. Additionally, more or less than four tubes and four wires may be used in accordance with the present invention.

5 In an alternative embodiment, instead of coating the inflatable tube with the conductive material as described above, a conductive object such as a plate, wire, ribbon, or the like, may be attached to the inflatable tube. Figs. 7A - 7B illustrate enlarged cross sectional views of the inflatable tube 200 with the attached conductive object 202. Figs. 7A - 7B illustrate the tube 200 in its deflated and inflated states. The conductive object 202 is attached to the tube 200 on a portion 204 such that
10 when the tube is inflated, the conductive object 202 will form a contact with the wafer 2. When the contact is made between the conductive object 202 and the wafer 2, a section 206 of the inflatable tube that is adjacent to the conductive object 202 forms a liquid tight seal against the wafer 2. This prevents the plating solution from making contact with the conductive object 202. The conductive material 202 can be attached to the inflatable tube 200 using any conventional method such as an
15 adhesive, or the like. Furthermore, a conductive wire or other conventional methods of applying an electric potential to the conductive object 202 may be used in accordance with the invention.

This invention enjoys general applicability in plating any of the various metals on any type of substrate, including Cu, Cu-alloys, Au, Ni, Pt, precious metal, lead-tin solder, lead-free solder, magnetic films such as permalloy and their respective alloys, during the manufacturing of
20 semiconductor devices on a semiconductor substrate. Also, the embodiments of the invention can be practiced in conventional apparatus that are adapted to employ an inflatable tube and a liquid chamber having a liquid conductor.

In the previous descriptions, numerous specific details are set forth, such as specific materials, structures, chemicals, processes, etc., to provide a thorough understanding of the present
25 invention. However, as one having ordinary skill in the art would recognize, the present invention can be practiced without resorting to the details specifically set forth.

Although various preferred embodiments of the invention have been disclosed for illustrative purposes, those skilled in the art will appreciate that various modifications, additions and/or substitutions are possible without departing from the scope and spirit of the present invention as
30 disclosed in the claims.

I claim:

1. A semiconductor workpiece plating apparatus for plating a front face of a semiconductor workpiece, comprising:
 - a workpiece support;
 - an anode;
 - a liquid conductor adapted to make an ohmic contact with the workpiece upon application of power; and
 - a chamber adapted to hold the liquid conductor when the liquid conductor makes the ohmic contact with the workpiece.
2. An apparatus according to claim 1, wherein the liquid conductor comprises one of indium, tin, gallium, mercury, acidic solution, and a salt solution.
3. An apparatus according to claim 1, wherein the liquid conductor comprises an alloy or a mixture from a group consisting of indium, tin, gallium, mercury, acidic solution, and a salt solution.
4. An apparatus according to claim 1 further comprising a wire coupled to the liquid conductor, wherein the wire is adapted to provide an electric potential to the liquid conductor.
5. An apparatus according to claim 1, wherein the liquid conductor is adapted to provide an electric potential to an entire circumferential edge of the workpiece.
6. An apparatus according to claim 1, wherein the liquid conductor is adapted to provide an electric potential to predetermined areas of a circumferential edge of the workpiece.
7. An apparatus according to claim 1 further comprising:
 - a tube adapted to prevent the liquid conductor from reaching a back face of the workpiece;and
 - a seal adapted to prevent the liquid conductor from reaching the front face of the workpiece.
8. An apparatus according to claim 7, wherein the tube is inflated with a gas.
9. An apparatus according to claim 7, wherein a section of the tube and a section of the seal form a part of the chamber.
10. An apparatus according to claim 1 further comprising:
 - one or more reservoirs adapted to store the liquid conductor;
 - one or more inlet channels, wherein the one or more inlet channels are used to flow the liquid conductor from the one or more reservoirs to the chamber; and
 - one or more outlet channels, wherein the one or more outlet channels are used to remove the liquid conductor from the chamber.

11. An apparatus according to claim 1, wherein the liquid conductor forms the ohmic contact with the workpiece such that plating is substantially uniform across the front face of the workpiece.
12. An apparatus according to claim 11, wherein the substantial uniformity is obtained when the liquid conductor makes ohmic contact with predetermined areas of a circumferential edge of the workpiece.
13. An apparatus according to claim 1, wherein the liquid conductor includes a metallic powder.
14. An apparatus according to claim 1, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.
15. A semiconductor workpiece plating apparatus for plating a front face of a semiconductor workpiece, comprising:
 - a workpiece support;
 - an anode; and
 - a tube adapted to make an ohmic contact with the workpiece, wherein the tube is coated with a conductive material and provides an electric potential to the workpiece upon application of power.
16. An apparatus according to claim 15, wherein the tube is inflated with a gas.
17. An apparatus according to claim 15, wherein the tube is formed from one of an elastomer and a reinforced elastomer.
18. An apparatus according to claim 15, wherein the conductive material comprises one of a metal and a polymer.
19. An apparatus according to claim 15 further comprising a wire coupled to the tube, wherein the wire is adapted to provide the electric potential to the tube.
20. An apparatus according to claim 15, wherein the tube is adapted to provide the electric potential to an entire circumferential edge of the workpiece.
21. An apparatus according to claim 15, wherein the tube is adapted to provide the electric potential to predetermined areas of a circumferential edge of the workpiece.
22. An apparatus according to claim 15 further comprising a seal positioned in between the tube and the front face of the workpiece, wherein the seal is adapted to prevent a plating solution from reaching the tube.
23. An apparatus according to claim 15, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.
24. A method for plating a surface of a semiconductor workpiece, the method comprising the steps of:

supporting the workpiece such that the surface of the workpiece is exposed to a plating solution, the plating solution being flowed between an anode and the workpiece;

providing an electric potential to a circumferential edge of the workpiece using a liquid conductor; and

plating the surface of the workpiece using the plating solution.

25. A method according to claim 24, wherein the step of providing the electric potential to the liquid conductor comprises the step of applying the electric potential to a wire coupled to the liquid conductor.

26. A method according to claim 24 further comprising the steps of:
inflating a tube, wherein the inflated tube prevents the liquid conductor from reaching a back face of the workpiece; and

injecting the liquid conductor into a chamber formed in part from the tube.

27. A method according to claim 26 further comprising the steps of:
injecting the liquid conductor into the chamber from a reservoir via an inlet channel; and
removing the liquid conductor from the chamber via an outlet channel.

28. A method according to claim 24, wherein the liquid conductor comprises one of indium, tin, gallium, mercury, acidic solution, and a salt solution.

29. A method according to claim 24, wherein the liquid conductor comprises an alloy or a mixture from a group consisting of indium, tin, gallium, mercury, acidic solution, and a salt solution.

30. A method according to claim 24, wherein the circumferential edge of the workpiece comprises an entire circumferential edge of the workpiece.

31. A method according to claim 24, wherein the circumferential edge of the workpiece comprises predetermined areas of the workpiece.

32. A method according to claim 24, wherein the liquid conductor includes a metallic powder.

33. A method according to claim 24, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.

34. A method for providing an electric potential to a surface a semiconductor workpiece, the method comprising the steps of:

supporting the workpiece;

injecting a liquid conductor into a chamber such that the liquid conductor makes ohmic contact with the surface of the workpiece;

providing an inflated tube such that the tube seals a back face of the workpiece from the liquid conductor; and

applying an electric potential to the liquid conductor in the chamber, thereby providing the electric potential to the surface of the workpiece.

35. A method according to claim 34, wherein the step of applying the electric potential to the liquid conductor comprises the step of applying the electric potential to a wire coupled to the liquid conductor.

36. A method according to claim 34, wherein the liquid conductor comprises one of indium, tin, gallium, mercury, acidic solution, and a salt solution.

37. A method according to claim 34, wherein the liquid conductor comprises an alloy or a mixture from a group consisting of indium, tin, gallium, mercury, acidic solution, and a salt solution.

38. A method according to claim 34, wherein the liquid conductor includes a metallic powder.

39. A method according to claim 34, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.

40. A method for plating a surface of a semiconductor workpiece, the method comprising the steps of:

supporting the workpiece such that the surface of the workpiece is exposed to a plating solution, the plating solution being flowed between an anode and the workpiece;

providing an electric potential to a circumferential edge of the workpiece using a conductive tube coated with a conductive material; and

plating the surface of the workpiece using the plating solution.

41. A method according to claim 40 further comprising the steps of:

inflating the conductive tube, wherein the inflated tube makes ohmic contact with the circumferential edge of the workpiece; and

providing the electric potential to the conductive tube.

42. A method according to claim 40, wherein the inflating step comprises the step of inflating the tube with a gas.

43. A method according to claim 40, wherein the tube is formed from one of an elastomer or a reinforced elastomer.

44. A method according to claim 40, wherein the step of providing the electric potential to the conductive tube comprises the step of applying the electric potential to a wire coupled to the conductive tube.

45. A method according to claim 40, wherein the conductive material comprises one of a metal and a polymer.

46. A method according to claim 40, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.

47. A method for providing an electric potential to a surface a semiconductor workpiece, the method comprising the steps of:

supporting the workpiece;

inflating a conductive tube coated with a conductive material such that the tube makes ohmic contact with the surface of the workpiece; and

applying an electric potential to the conductive tube, thereby providing the electric potential to the surface of the workpiece.

48. A method according to claim 47, wherein the step of applying the electric potential to the tube comprises the step of applying the electric potential to a wire coupled to the tube.

49. A method according to claim 47, wherein the surface of the workpiece comprises an entire circumferential edge of the workpiece.

50. A method according to claim 47, wherein the surface of the workpiece comprises predetermined areas of the workpiece.

51. A method according to claim 47, wherein the conductive material comprises one of a metal and a polymer.

52. A method according to claim 47, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.

53. An apparatus for removing a metal layer from a circumferential edge of a semiconductor workpiece using an etching solution, comprising:

a workpiece support;

a chamber adapted to hold the etching solution while the etching solution removes the metal layer from the circumferential edge of the workpiece;

a tube adapted to prevent the etching solution from reaching a back face of the workpiece;

and

a seal adapted to prevent the etching solution from reaching a front face of the workpiece.

54. An apparatus according to claim 53, wherein the etching solution is adapted to remove the metal layer from the entire circumferential edge of the workpiece.

55. An apparatus according to claim 53, wherein the etching solution is adapted to remove the metal layer from predetermined areas of the circumferential edge of the workpiece.

56. An apparatus according to claim 53, wherein a section of the tube and a section of the seal form a part of the chamber.

57. An apparatus according to claim 53, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.

58. A method for removing a metal layer from a circumferential edge of a semiconductor workpiece, the method comprising the steps of:

supporting the workpiece such that the circumferential edge of the workpiece is exposed an etching solution;

inflating a tube, wherein the inflated tube prevents the etching solution from reaching a back face of the workpiece; and

injecting the etching solution into a chamber, wherein the etching solution removes the metal layer from the circumferential edge of the workpiece.

59. A method according to claim 58, wherein the tube is formed from one of an elastomer and a reinforced elastomer.

60. A method according to claim 58, wherein the circumferential edge of the workpiece comprises an entire circumferential edge of the workpiece.

61. A method according to claim 58, wherein the circumferential edge of the workpiece comprises predetermined areas of the workpiece.

62. A method according to claim 58, wherein the workpiece comprises one of a wafer, flat panel, and a magnetic film.

63. A semiconductor workpiece plating apparatus for plating a front face of a semiconductor workpiece, comprising:

a workpiece support;

an anode;

an inflatable tube; and

a conductive object attached to the inflatable tube, wherein the conductive object is adapted to make an ohmic contact with the workpiece and provides an electric potential to the workpiece upon application of power.

64. An apparatus according to claim 63, wherein the conductive object comprises one of a plate, a ribbon, and a wire.

65. A method for plating a surface of a semiconductor workpiece, the method comprising the steps of:

supporting the workpiece such that the surface of the workpiece is exposed to a plating solution, the plating solution being flowed between an anode and the workpiece;

providing an electric potential to a circumferential edge of the workpiece using a conductive object attached to an inflatable tube; and

plating the surface of the workpiece using the plating solution.

66. A method according to claim 65, wherein the conductive object comprises one of a plate, a ribbon, and a wire.

67. A method for providing an electric potential to a surface a semiconductor workpiece, the method comprising the steps of:

supporting the workpiece;

inflating a tube having a conductive object such that the conductive object makes ohmic contact with the surface of the workpiece; and

applying an electric potential to the conductive object, thereby providing the electric potential to the surface of the workpiece.

68. A method according to claim 67, wherein the conductive object comprises one of a plate, a ribbon, and a wire.

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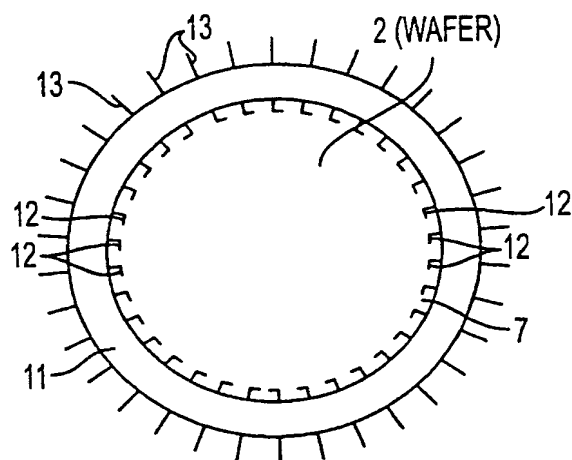


FIG. 1A
(PRIOR ART)

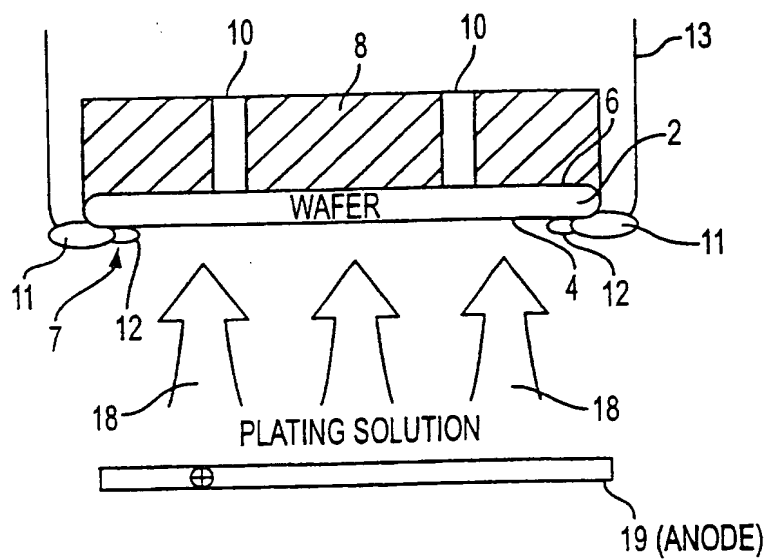


FIG. 1B
(PRIOR ART)

INTERNATIONAL SEARCH REPORT

International Application No

PCT/US 00/08478

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 H01L21/00

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 H01L C25D

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data, PAJ

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	GB 1 350 070 A (INTERNATIONAL COMPUTERS LIMITED) 18 April 1974 (1974-04-18) the whole document	1-6, 24, 25, 28-31
A	---	34-37, 53, 58
A	FR 2 763 343 A (MOTOROLA) 20 November 1998 (1998-11-20) abstract; figure 3	1, 24, 34, 53, 58
A	PATENT ABSTRACTS OF JAPAN vol. 018, no. 392 (C-1228), 22 July 1994 (1994-07-22) -& JP 06 108285 A (TOSHIBA CORP; OTHERS: 01), 19 April 1994 (1994-04-19) abstract	1, 24, 34, 53, 58

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☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

* Special categories of cited documents :

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
- *L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)
- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

- *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
- *&* document member of the same patent family

Date of the actual completion of the international search

6 November 2000

Date of mailing of the international search report

17. 11. 00

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Oberle, T

INTERNATIONAL SEARCH REPORT

International Application No

PCT/US 00/08478

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	PATENT ABSTRACTS OF JAPAN vol. 1999, no. CO, 31 May 1999 (1999-05-31) -& JP 11 054479 A (SONY CORP), 26 February 1999 (1999-02-26) abstract	1, 24, 34, 53, 58
X	WO 97 01657 A (TOOLEX ALPHA) 16 January 1997 (1997-01-16) abstract; figure 1 page 3, line 25 -page 4, line 29	15, 17, 18, 20, 22, 40, 43, 45
Y		16, 19, 21, 23, 41, 42, 44, 46-52 63, 65
A		
X	US 5 429 733 A (ISHIDA) 4 July 1995 (1995-07-04) abstract; figures 1-4 column 3, line 8-30	63-68
Y		16, 19, 21, 23, 41, 42, 44, 46-52
A		1, 15, 24, 34, 40, 53, 58
X	US 5 871 626 A (CRAFTS ET AL.) 16 February 1999 (1999-02-16) abstract; figures 3, 9 column 6, line 39-48	63-68
A		15, 16, 22, 23, 40-42, 46, 47, 49, 51, 52

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

PCT/US 00/08478

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
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		JP 2000500825 T	25-01-2000
		WO 9712079 A	03-04-1997

FURTHER INFORMATION CONTINUED FROM PCT/ISA/ 210

This International Searching Authority found multiple (groups of) inventions in this international application, as follows:

1. Claims: 1-14,24-39,53-62

Annular chamber containing a liquid

2. Claims: 15-23,40-52,63-68

Circular tube coated with a conductive material

INTERNATIONAL SEARCH REPORT

International application No.
PCT/US 00/08478

Box I Observations where certain claims were found unsearchable (Continuation of item 1 of first sheet)

This International Search Report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:

1. ☐ Claims Nos.:
because they relate to subject matter not required to be searched by this Authority, namely:
2. ☐ Claims Nos.:
because they relate to parts of the International Application that do not comply with the prescribed requirements to such an extent that no meaningful International Search can be carried out, specifically:
3. ☐ Claims Nos.:
because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a).

Box II Observations where unity of invention is lacking (Continuation of item 2 of first sheet)

This International Searching Authority found multiple inventions in this international application, as follows:

see additional sheet

1. ☒ As all required additional search fees were timely paid by the applicant, this International Search Report covers all searchable claims.
2. ☐ As all searchable claims could be searched without effort justifying an additional fee, this Authority did not invite payment of any additional fee.
3. ☐ As only some of the required additional search fees were timely paid by the applicant, this International Search Report covers only those claims for which fees were paid, specifically claims Nos.:
4. ☐ No required additional search fees were timely paid by the applicant. Consequently, this International Search Report is restricted to the invention first mentioned in the claims; it is covered by claims Nos.:

Remark on Protest

- ☐ The additional search fees were accompanied by the applicant's protest.
- ☒ No protest accompanied the payment of additional search fees.

FURTHER INFORMATION CONTINUED FROM PCT/ISA/ 210

This International Searching Authority found multiple (groups of) inventions in this international application, as follows:

1. Claims: 1-14,24-39,53-62

Annular chamber containing a liquid

2. Claims: 15-23,40-52,63-68

Circular tube coated with a conductive material

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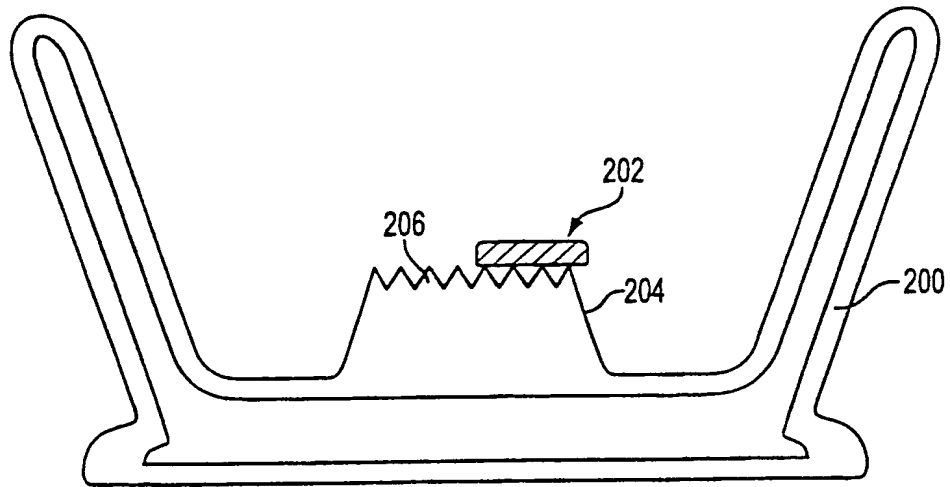


FIG. 7A

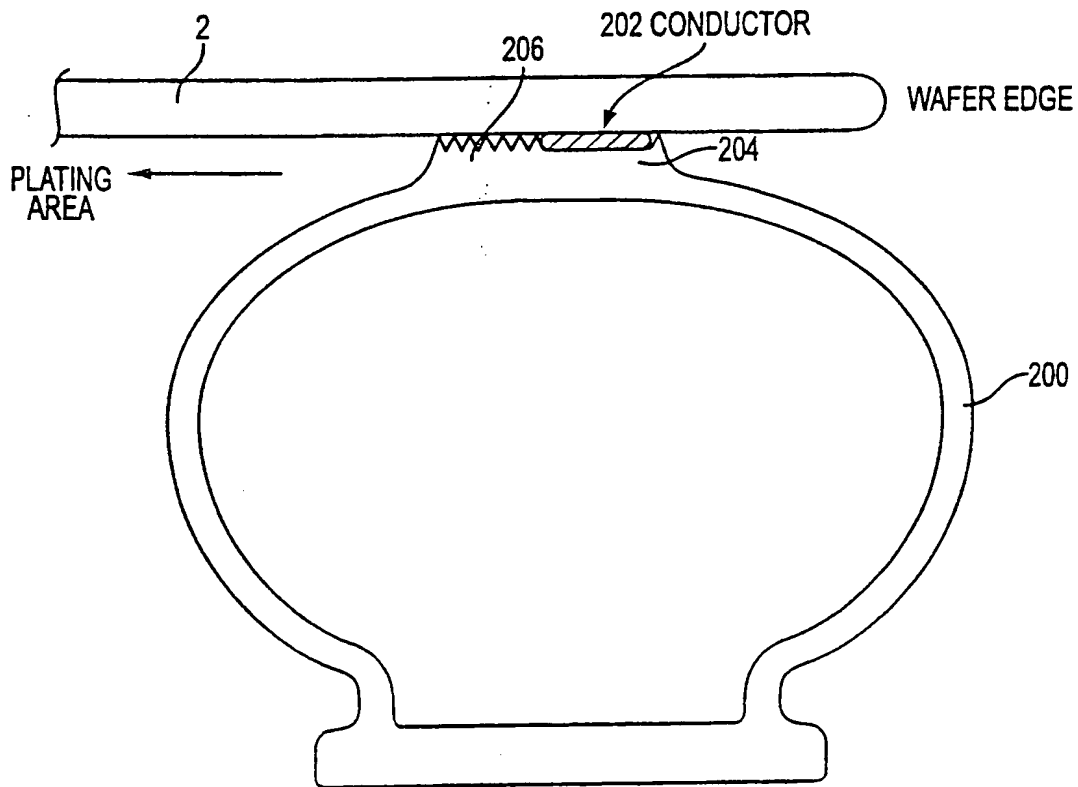


FIG. 7B

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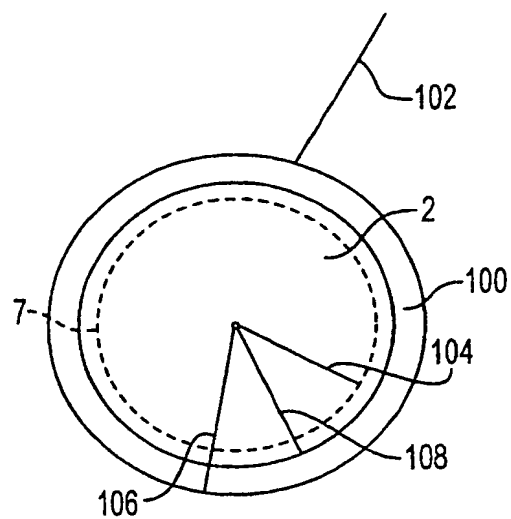


FIG. 6A

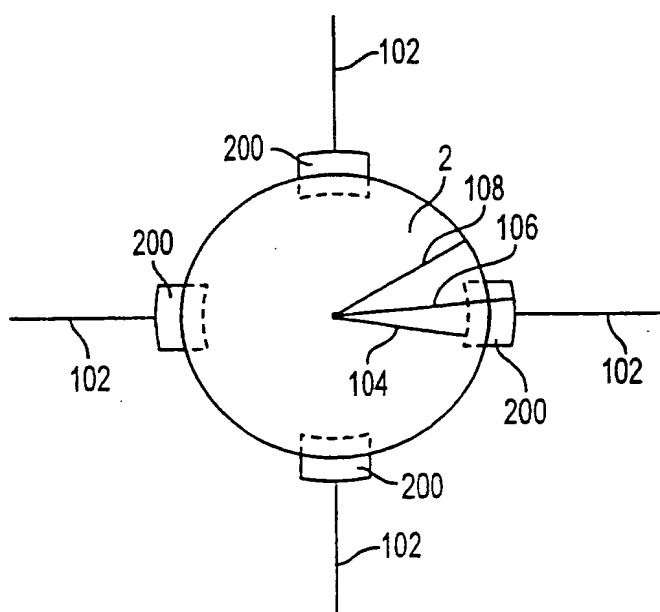


FIG. 6B

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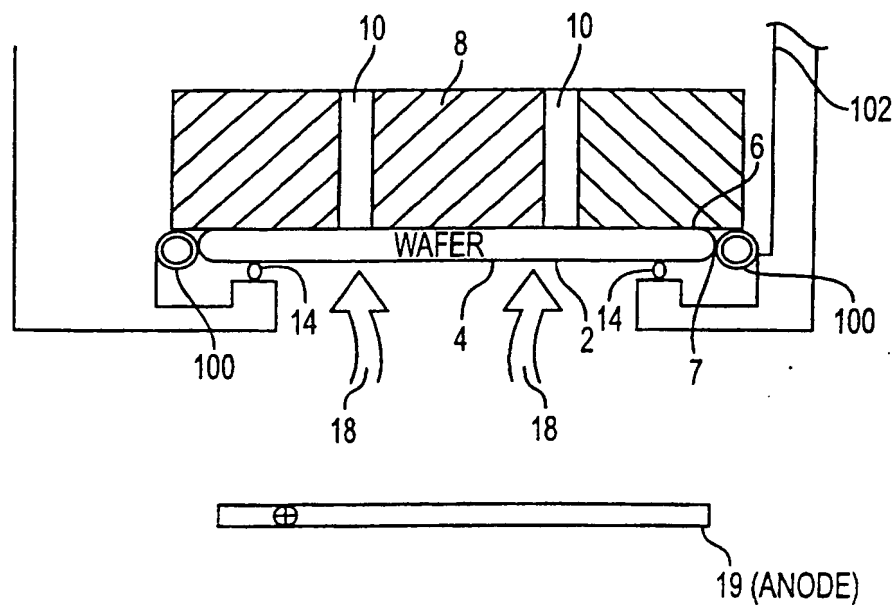


FIG. 5

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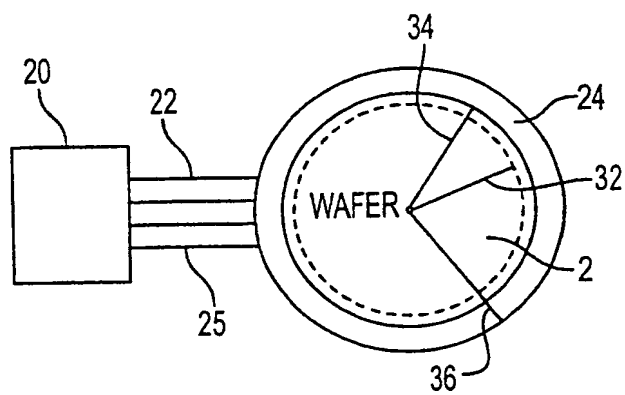


FIG. 4A

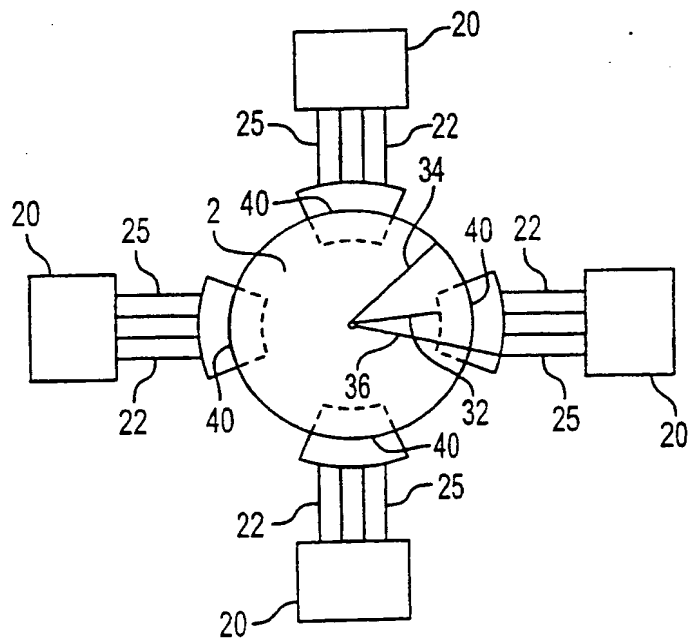


FIG. 4B

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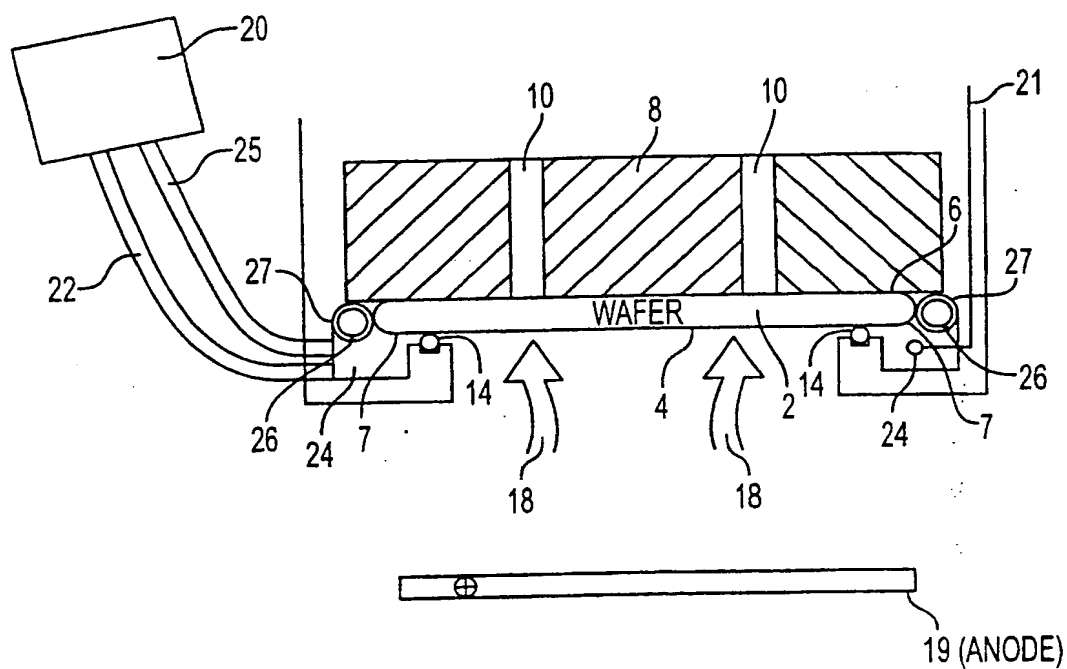


FIG. 2

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